

Notic of R ferences Cited	Application/Control No. 09/738,362	Applicant(s)/Patent Under Reexamination NOGUCHI ET AL.	
	Examiner Peter J Lish	Art Unit 1754	Page 1 of 1

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	B	US-5,956,225	09-1999	Okuyama et al.	29/25.03
	C	US-6,072,692	06-2000	Hiratsuka et al.	29/25.03
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*	U	Setoyama et al., "Simulation Study on the Relationship Between a High Resolution as-Plot and the Pore Size Distribution for Activated Carbon", 1998, Carbon 36(10), pages 1459-1467
*	V	Hiratsuka et al., "Evaluation of Activated Carbon Electrodes for Electric Double Layer Capacitors Using an Organic Electrolyte Solution", 1991, Denki Kagaku 59(7), pages 607-613
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.